

# Contents

<b>1</b>	<b>Introduction: History</b>	<b>1</b>
1.1	The Early Years	1
1.2	The Postwar Revival	6
	References	13
<b>2</b>	<b>Basic Interactions</b>	<b>21</b>
2.1	Fundamental Theories of Electron Emission	21
2.2	Photoemission	25
2.2.1	General Considerations	25
2.2.2	The Free Electron Gas Approximation	27
2.2.3	Band Structure UV Photoemission	30
2.2.4	Spin Effects in UV Photoemission	37
2.2.5	Surface Plasmon Photoemission	41
2.2.6	X-Ray Photoemission	47
2.3	Electron Reflection	64
2.3.1	General Considerations	64
2.3.2	Elastic Scattering	64
2.3.3	Inelastic Scattering	67
2.3.4	Surface Effects	69
2.3.5	VLEED, LEETS, TCS	72
2.3.6	Quantum Well Effects	75
2.3.7	Other Aspects	76
	References	78
<b>3</b>	<b>Instrumentation</b>	<b>89</b>
3.1	Instruments: From Simple to Complex	89
3.1.1	PEEM	89
3.1.2	LEEM	94
3.1.3	Aberration-Corrected Instruments	101

3.1.4	Spectroscopic Imaging Instruments . . . . .	106
3.1.5	Spin-Resolved Imaging Systems . . . . .	109
3.2	Components . . . . .	114
3.2.1	Objective Lens and Other Axial-Symmetric Lenses . . . . .	114
3.2.2	Magnetic Deflectors . . . . .	125
3.2.3	Electron Mirrors . . . . .	130
3.2.4	Aberration Correctors . . . . .	131
3.2.5	Energy Filters . . . . .	136
3.2.6	Wien Filters . . . . .	140
3.2.7	Photon Sources . . . . .	143
3.2.8	Electron Sources . . . . .	153
3.2.9	Other Components (Image Detectors Vacuum System Including Airlock and Specimen Preparation Chamber, Electronics) . . . . .	163
References . . . . .		173
<b>4</b>	<b>Theory of Image Formation . . . . .</b>	<b>189</b>
4.1	Introduction . . . . .	189
4.2	Wave Propagation: The Contrast Transfer Function . . . . .	193
4.2.1	Low Energy Electron Microscopy: The Wave Amplitude . . . . .	193
4.2.2	The Image Intensity . . . . .	205
4.2.3	Mirror Electron Microscopy . . . . .	212
4.2.4	Emission Electron Microscopy . . . . .	215
4.3	Through-Focus Series Image Improvement . . . . .	218
4.4	Information Transfer in the Image Acquisition System . . . . .	221
4.5	Summary and Outlook . . . . .	224
References . . . . .		225
<b>5</b>	<b>Applications in Surface Science . . . . .</b>	<b>229</b>
5.1	Surface Microstructure . . . . .	229
5.1.1	Metals . . . . .	230
5.1.2	Semiconductors . . . . .	239
5.1.3	Other Inorganic Semiconductors . . . . .	258
5.1.4	Other Inorganic Compounds . . . . .	260
5.2	Adsorption . . . . .	264
5.2.1	Adsorption on Metals . . . . .	264
5.2.2	Adsorption on Semiconductors . . . . .	278
5.3	Film Growth and Structure . . . . .	284
5.3.1	Films on Semiconductors . . . . .	284
5.3.2	Films on Metals . . . . .	299
5.3.3	Organic Films . . . . .	308
References . . . . .		320

<b>6 Applications in Other Fields</b>	347
6.1 Graphene	347
6.1.1 Introduction	347
6.1.2 Graphene on SiC	350
6.1.3 Graphene on Metals	357
6.2 Plasmons	367
6.2.1 Introduction	367
6.2.2 Linear Structures	368
6.2.3 Nanostructures	372
6.2.4 Complex Wave Fields	377
6.2.5 Limitations	381
6.3 Technological Applications	382
6.3.1 General Materials Applications	382
6.3.2 Electronics	384
6.4 Biology	389
6.5 A Multimethod Case Study	392
References	395
<b>7 Magnetic Imaging</b>	409
7.1 Introduction	409
7.2 Ferromagnetic Films	414
7.2.1 Single Layers	415
7.2.2 Quantum Well Effects	419
7.2.3 Bilayers	421
7.2.4 Trilayers	423
7.2.5 Multilayers	426
7.2.6 Compound Layers	427
7.3 Bulk Magnetic Materials	429
7.3.1 Ferromagnetic Materials	429
7.3.2 Antiferromagnetic Materials	431
7.4 Ferromagnet–Antiferromagnet Interfaces	433
7.5 Magnetic Nanostructures	436
7.5.1 Introduction	436
7.5.2 Static Domain Structure	437
7.5.3 Field and Current Influence	440
7.5.4 Nanodots and Nanostructure Arrays	444
7.6 Ferroelectrics/Multiferroics	447
7.6.1 Ferroelectrics	447
7.6.2 Multiferroics	448
References	451
<b>8 Other Surface Imaging Methods with Electrons</b>	465
8.1 Scanning Low Energy Electron Microscopy	465
8.2 Scanning Low Energy Electron Diffraction Microscopy	467
8.3 Reflection Electron Microscopy	467

8.4	Secondary and Auger Electron Microscopy . . . . .	470
8.5	Scanning Electron Microscopy with Spin Analysis . . . . .	471
8.6	Scanning Photoemission Microscopy . . . . .	473
8.7	Concluding Remarks . . . . .	475
	References . . . . .	475
<b>Index</b>	. . . . .	<b>479</b>

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